

Notice of References Cited	Application/Control No. 10/763,541	Applicant(s)/Patent Under Reexamination YARIV, AMNON	
	Examiner John D. Lee <i>John D. Lee</i>	Art Unit 2874	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	D	US-6,061,381	05-2000	Adams et al.	372/96
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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